

1GB – 128Mx72 DDR2 SDRAM RDIMM, VLP

FEATURES

- VLP (very low profile) 240-pin, dual in-line memory module
- Fast data transfer rates: PC2-6400*, PC2-5300*, PC2-4300 and PC2-3200
- Utilizes 800*, 667*, 533 and 400 Mb/s DDR2 SDRAM components
- Vcc = Vccq = 1.8V
- JEDEC standard 1.8V I/O (SSTL_18-compatible)
- Differential data strobe (DQS, DQS#) option
- Four-bit prefetch architecture
- DLL to align DQ and DQS transitions with CK
- Multiple internal device banks for concurrent operation
- Supports duplicate output strobe (RDQS/RDQS#)
- Programmable CAS# latency (CL): 3, 4, 5* and 6*
- Adjustable data-output drive strength
- On-die termination (ODT)
- Posted CAS# latency: 0, 1, 2, 3 and 4
- Serial Presence Detect (SPD) with EEPROM
- Auto & self refresh (64ms: 8,192 cycle refresh)
- Gold edge contacts
- RoHS compliant
- Package option
 - 240 Pin DIMM VLP
 - PCB – 18.29mm (0.720") Max

DESCRIPTION

The WV3HG128M72AER is a 128Mx72 Double Data Rate DDR2 SDRAM high density module. This memory module consists of eighteen 128Mx4 bit with 4 banks DDR2 Synchronous DRAMs in FBGA packages, mounted on a VLP 240-pin DIMM FR4 substrate.

* This product is under development, is not qualified or characterized and is subject to change or cancellation without notice.

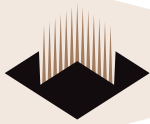
NOTE: Consult factory for availability of:

- Vendor source control options
- Industrial temperature option

OPERATING FREQUENCIES

	PC2-3200	PC2-4300	PC2-5300*	PC2-6400*
Clock Speed	200MHz	266MHz	333MHz	400MHz
CL-tRCD-tRP	3-3-3	4-4-4	5-5-5	6-6-6

* Consult factory for availability



PIN CONFIGURATION

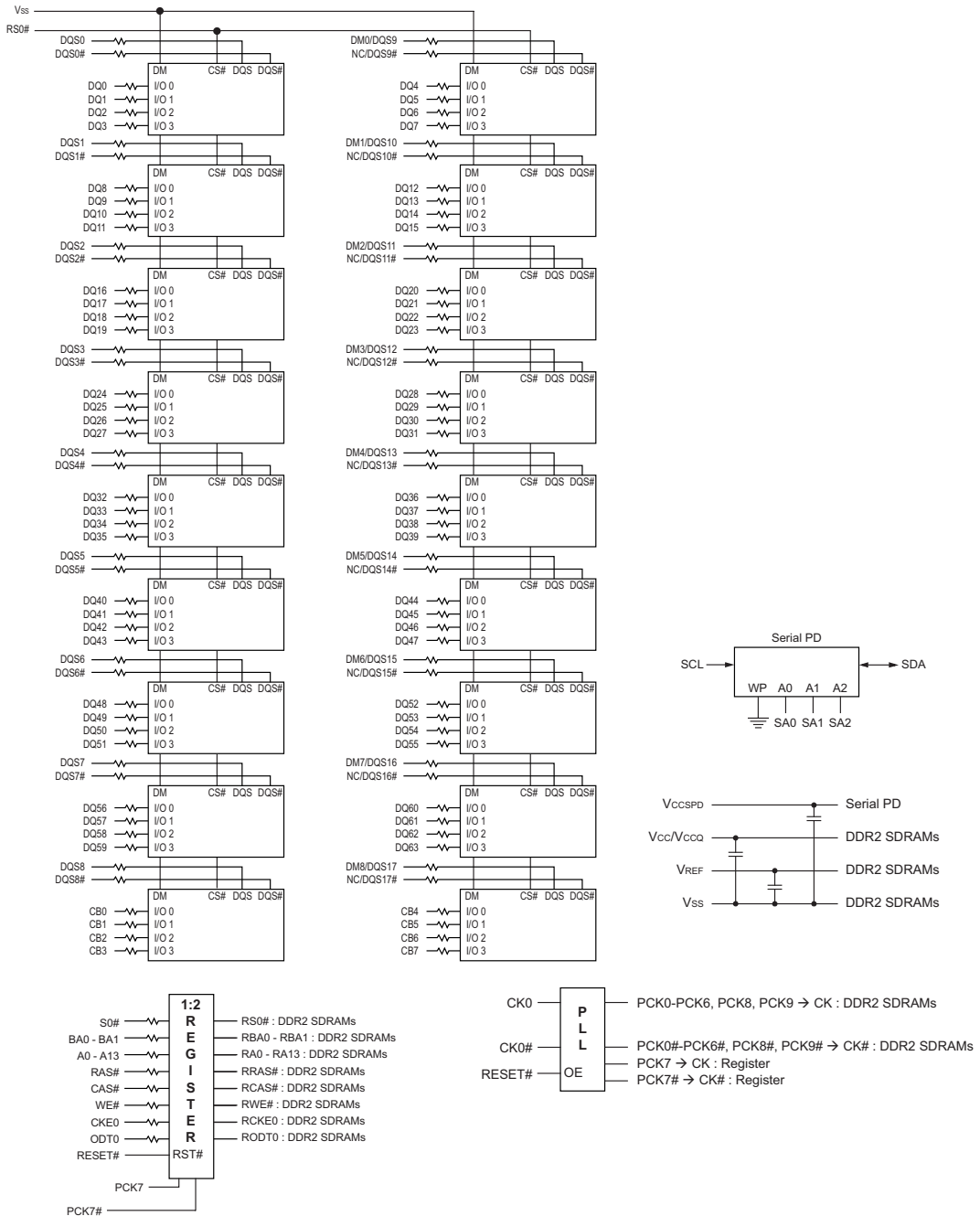
Pin No.	Symbol	Pin No.	Symbol	Pin No.	Symbol	Pin No.	Symbol
1	V _{REF}	61	A4	121	V _{SS}	181	V _{CC0}
2	V _{SS}	62	V _{CC0}	122	DO4	182	A3
3	DO0	63	A2	123	DO5	183	A1
4	DO1	64	V _{CC}	124	V _{SS}	184	V _{CC}
5	V _{SS}	65	V _{SS}	125	DM0/DQS9	185	CK0
6	DQS0#	66	V _{SS}	126	NC/DQS9#	186	CK0#
7	DQS0	67	V _{CC}	127	V _{SS}	187	V _{CC}
8	V _{SS}	68	NC	128	DO6	188	A0
9	DO2	69	V _{CC}	129	DO7	189	V _{CC}
10	DO3	70	A10/AP	130	V _{SS}	190	BA1
11	V _{SS}	71	BA0	131	DO12	191	V _{CC0}
12	DO8	72	V _{CC0}	132	DO13	192	RAS#
13	DO9	73	WE#	133	V _{SS}	193	SO#
14	V _{SS}	74	CAS#	134	DM1/DQS10	194	V _{CC0}
15	DQS1#	75	V _{CC0}	135	NC/DQS10#	195	ODT0
16	DQS1	76	NC	136	V _{SS}	196	A13
17	V _{SS}	77	NC	137	NC	197	V _{CC}
18	RESET#	78	V _{CC0}	138	NC	198	V _{SS}
19	NC	79	V _{SS}	139	V _{SS}	199	DQ36
20	V _{SS}	80	DO32	140	DO14	200	DO37
21	DO10	81	DO33	141	DO15	201	V _{SS}
22	DO11	82	V _{SS}	142	V _{SS}	202	DM4/DQS13
23	V _{SS}	83	DQS4#	143	DO20	203	NC/DQS13#
24	DO16	84	DQS4	144	DO21	204	V _{SS}
25	DO17	85	V _{SS}	145	V _{SS}	205	DO38
26	V _{SS}	86	DQ34	146	DM2/DQS11	206	DQ39
27	DQS2#	87	DO35	147	NC/DQS11#	207	V _{SS}
28	DQS2	88	V _{SS}	148	V _{SS}	208	DO44
29	V _{SS}	89	DO40	149	DO22	209	DO45
30	DO18	90	DO41	150	DO23	210	V _{SS}
31	DO19	91	V _{SS}	151	V _{SS}	211	DM5/14
32	V _{SS}	92	DQS5#	152	DO28	212	NC/DQS14#
33	DO24	93	DQS5	153	DO29	213	V _{SS}
34	DO25	94	V _{SS}	154	V _{SS}	214	DO46
35	V _{SS}	95	DO42	155	DM3/DQS12	215	DQ47
36	DQS3#	96	DO43	156	NC/DQS12#	216	V _{SS}
37	DQS3	97	V _{SS}	157	V _{SS}	217	DO52
38	V _{SS}	98	DO48	158	DO30	218	DO53
39	DO26	99	DO49	159	DO31	219	V _{SS}
40	DO27	100	V _{SS}	160	V _{SS}	220	NC
41	V _{SS}	101	SA2	161	CB4	221	NC
42	CB0	102	NC	162	CB5	222	V _{SS}
43	CB1	103	V _{SS}	163	V _{SS}	223	DM6/DQS15
44	V _{SS}	104	DQS6#	164	DM8/DQS17	224	NC/DQS15#
45	DQS8#	105	DQS6	165	NC/DQS17#	225	V _{SS}
46	DQS8	106	V _{SS}	166	V _{SS}	226	DO54
47	V _{SS}	107	DO50	167	CB6	227	DO55
48	CB2	108	DO51	168	CB7	228	V _{SS}
49	CB3	109	V _{SS}	169	V _{SS}	229	DO60
50	V _{SS}	110	DO56	170	V _{CC0}	230	DO61
51	V _{CC0}	111	DO57	171	NC	231	V _{SS}
52	CKE0	112	V _{SS}	172	V _{CC}	232	DM7/DQS16
53	V _{CC}	113	DQS7#	173	NC	233	NC/DQS16#
54	NC	114	DQS7	174	NC	234	V _{SS}
55	NC	115	V _{SS}	175	V _{CC0}	235	DO62
56	V _{CC0}	116	DO58	176	A12	236	DO63
57	A11	117	DO59	177	A9	237	V _{SS}
58	A7	118	V _{SS}	178	V _{CC}	238	V _{CC} SPD
59	V _{CC}	119	SDA	179	A8	239	SA0
60	A5	120	SCL	180	A6	240	SA1

PIN NAMES

Pin Name	Function
CK0,CK0#	Clock Inputs
CKE0	Clock Enable
CB0-CB7	Check Bits
RAS#	Row Address Strobe
CAS#	Column Address Strobe
WE#	Write Enable
S0#	Chip Select
A0-A13	Address Inputs
BA0,BA1	SDRAM Bank Address
ODT0	On-die termination control
SCL	SPD Clock Input
SDA	SPD Data Input/Output
SA0-SA2	SPD address
DO0-DO63	Data Input/Output
DM0-DM8	Data Masks
DQS0-DQS17	Data strobes
DQS0#-DQS17#	Data strobes complement
V _{CC} , V _{CC0}	Core and I/O Power
V _{SS}	Ground
V _{REF}	Input/Output Reference
V _{CC} SPD	SPD Power
NC	No connect
RESET#	Reset Input



FUNCTIONAL BLOCK DIAGRAM



NOTE: All resistor values are 22 ohms unless otherwise specified.



DC OPERATING CONDITIONS

All voltages referenced to V_{SS}

Parameter	Symbol	Min	Typical	Max	Unit	Notes
Supply Voltage	V _{CC}	1.7	1.8	1.9	V	3
I/O Reference Voltage	V _{REF}	0.49 x V _{CC}	0.50 x V _{CC}	0.51 x V _{CC}	V	1
I/O Termination Voltage	V _{TT}	V _{REF} -0.04	V _{REF}	V _{REF} +0.04	V	2
SPD Supply Voltage	V _{CCSPD}	1.7	-	3.6	V	

Notes:

- V_{REF} is expected to equal V_{CC/2} of the transmitting device and to track variations in the DC level of the same. Peak-to-peak noise on V_{REF} may not exceed +/-1 percent of the DC value. Peak-to-peak AC noise on V_{REF} may not exceed +/-2 percent of V_{REF}. This measurement is to be taken at the nearest V_{REF} bypass capacitor.
- V_{TT} is not applied directly to the device. V_{TT} is a system supply for signal termination resistors, is expected to be set equal to V_{REF} and must track variations in the DC level of V_{REF}.
- V_{CCO} of all IC's are tied to V_{CC}.

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Min	Max	Units	
V _{CC}	Voltage on V _{CC} pin relative to V _{SS}	-0.5	2.3	V	
V _{IN} , V _{OUT}	Voltage on any pin relative to V _{SS}	-0.5	2.3	V	
T _{STG}	Storage Temperature	-55	100	°C	
I _L	Input leakage current; Any input 0V<V _{IN} <V _{CC} ; V _{REF} input 0V,V _{IN} ,0.95V; Other pins not under test = 0V	Command/Address, RAS#, CAS#, WE#,	-5	5	μA
		CK, CK#	-10	10	μA
		DM	-2	2	μA
I _{OZ}	Output leakage current; 0V<V _{IN} <V _{CC} ; DQs and ODT are disable	DQ, DQS, DQS#	-5	5	μA
I _{VREF}	V _{REF} leakage current; V _{REF} = Valid V _{REF} level	-36	36	μA	
PD	Power dissipaion	18		W	

CAPACITANCE

T_A = 25°C, f = 100MHz, V_{CC} = V_{CCO} = 1.8V

Parameter	Symbol	Max	Units
Input Capacitance: CK, CK#	C _{CK}	11	pF
Input Capacitance: CKE, CS#	C _{I1}	12	pF
Input Capacitance: Addr. RAS#, CAS#, WE#	C _{I2}	12	pF
Input/Output Capacitance: DQ, DQS, DM, DQS#	C _{IO}	10	pF

Note: Based on SAMSUNG components



OPERATING TEMPERATURE CONDITION

Parameter	Symbol	Rating	Units	Notes
Operating Case Temperature (Commercial)	TOPER	0 to +85°C	°C	1, 2

- NOTE:
1. Operation temperature is the case surface temperature on the center/top side of the DRAM. For the measurement conditions, please refer to JEDEC JESD51.2
 2. At 0 - 85°C, operation temperature range, all DRAM specification will be supported.

INPUT DC LOGIC LEVEL

All voltages referenced to V_{SS}

Parameter	Symbol	Min	Max	Unit
Input High (Logic 1) Voltage	V _{IH} (DC)	V _{REF} + 0.125	V _{CC} + 0.300	V
Input High (Logic 0) Voltage	V _{IL} (DC)	-0.300	V _{REF} - 0.125	V

INPUT AC LOGIC LEVEL

All voltages referenced to V_{SS}

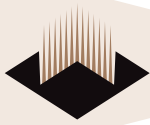
Parameter	Symbol	Min	Max	Unit
AC Input High (Logic 1) Voltage	V _{IH} (AC)	V _{REF} + 0.250	-	V
AC Input High (Logic 0) Voltage	V _{IL} (AC)	-	V _{REF} - 0.250	V

INPUT/OUTPUT CAPACITANCE

T_A=25°C, f=100MHz

Parameter	Symbol	Min	Max	Unit
Input capacitance (0A-A13, BA0-BA1, RAS#, CAS#, WE#)	C _{IN1}	6.5	7.5	pF
Input capacitance (CKE0), (ODT0)	C _{IN2}	6.5	7.5	pF
Input capacitance (CS0#)	C _{IN3}	6.5	7.5	pF
Input capacitance (CK0, CK0#)	C _{IN4}	6	7	pF
Input capacitance (DQS0 ~ DQS17, DQS0# ~ DQS17#)	C _{IN5} (534, 403)	6.5	8	pF
Input capacitance (DQ0~DQ63), (CB0~CB7)	C _{OUT1} (534, 403)	6.5	8	pF

Notes: Based on ELPIDA components

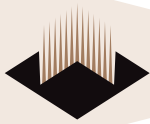


DDR2 I_{CC} SPECIFICATIONS AND CONDITIONS

V_{CC} = +1.8V ± 0.1V

Symbol	Proposed Conditions	534	403	Units	
I _{CC0}	Operating one bank active-precharge current; t _{CK} = t _{CK} (I _{CC}), t _{RC} = t _{RC} (I _{CC}), t _{RAS} = t _{RASmin} (I _{CC}); CE is HIGH, CS# is HIGH between valid commands; Address bus inputs are SWITCHING; Data bus inputs are SWITCHING	2,420	2,250	mA	
I _{CC1}	Operating one bank active-read-precharge current; I _{OUT} = 0mA; BL = 4, CL = CL(I _{CC}), AL = 0; t _{CK} = t _{CK} (I _{CC}), t _{RC} = t _{RC} (I _{CC}), t _{RAS} = t _{RASmin} (I _{CC}), t _{RCD} = t _{RCD} (I _{CC}); CE is HIGH, CS# is HIGH between valid commands; Address bus inputs are SWITCHING; Data pattern is same as I _{DAD6W}	2,640	2,400	mA	
I _{CC2P}	Precharge power-down current; All banks idle; t _{CK} = t _{CK} (I _{CC}); CE is LOW; Other control and address bus inputs are STABLE; Data bus inputs are FLOATING	784	724	mA	
I _{CC2Q}	Precharge quiet standby current; All banks idle; t _{CK} = t _{CK} (I _{CC}); CE is HIGH, CS# is HIGH; Other control and address bus inputs are STABLE; Data bus inputs are FLOATING	1,110	1,040	mA	
I _{CC2N}	Precharge standby current; All banks idle; t _{CK} = t _{CK} (I _{CC}); CE is HIGH, CS# is HIGH; Other control and address bus inputs are SWITCHING; Data bus inputs are SWITCHING	1,090	1,130	mA	
I _{CC3P}	Active power-down current; All banks open; t _{CK} = t _{CK} (I _{CC}); CE is LOW; Other control and address bus inputs are STABLE; Data bus inputs are FLOATING	Fast PDN Exit MRS(12) = 0	1,190	1,190	mA
		Slow PDN Exit MRS(12) = 1	600	570	mA
I _{CC3N}	Active standby current; All banks open; t _{CK} = t _{CK} (I _{CC}), t _{RAS} = t _{RASmax} (I _{CC}), t _{RP} = t _{RP} (I _{CC}); CE is HIGH, CS# is HIGH between valid commands; Other control and address bus inputs are SWITCHING; Data bus inputs are SWITCHING	1,840	1,730	mA	
I _{DAD6W}	Operating burst write current; All banks open, Continuous burst writes; BL = 4, CL = CL(I _{CC}), AL = 0; t _{CK} = t _{CK} (I _{CC}), t _{RAS} = t _{RASmax} (I _{CC}), t _{TRP} = t _{TRP} (I _{CC}); CE is HIGH, CS# is HIGH between valid commands; Address bus inputs are SWITCHING; Data bus inputs are SWITCHING	3,820	2,900	mA	
I _{DAD6R}	Operating burst read current; All banks open, Continuous burst reads, I _{OUT} = 0mA; BL = 4, CL = CL(I _{CC}), AL = 0; t _{CK} = t _{CK} (I _{CC}), t _{RAS} = t _{RASmax} (I _{CC}), t _{TRP} = t _{TRP} (I _{CC}); CE is HIGH, CS# is HIGH between valid commands; Address bus inputs are SWITCHING; Data pattern is same as I _{DAD6W}	3,590	3,000	mA	
I _{CC5B}	Burst auto refresh current; t _{CK} = t _{CK} (I _{CC}); Refresh command at every t _{RFC} (I _{CC}) interval; CE is HIGH, CS# is HIGH between valid commands; Other control and address bus inputs are SWITCHING; Data bus inputs are SWITCHING	4,150	3,880	mA	
I _{CC6}	Self refresh current; CK and CK# at 0V; CE 0.2V; Other control and address bus inputs are FLOATING; Data bus inputs are FLOATING	99	99	mA	
I _{CC7}	Operating bank interleave read current; All bank interleaving reads, I _{OUT} = 0mA; BL = 4, CL = CL(I _{CC}), AL = t _{RCD} (I _{CC}) - 1 * t _{CK} (I _{CC}); t _{CK} = t _{CK} (I _{CC}), t _{RC} = t _{RC} (I _{CC}), t _{RRD} = t _{RRD} (I _{CC}), t _{RCD} = 1 * t _{CK} (I _{CC}); CE is HIGH, CS# is HIGH between valid commands; Address bus inputs are STABLE during DESELECTs; Data pattern is same as I _{DAD6R} ; Refer to the following page for detailed timing conditions	5,900	5,570	mA	

Note: I_{CC} specification is based on SAMSUNG components. Other DRAM Manufacturers specification may be different.



DDR2 I_{CC} SPECIFICATIONS AND CONDITIONS

V_{CC} = +1.8V ± 0.1V

Symbol	Proposed Conditions	534	403	Units	
I _{CC0}	Operating one bank active-precharge current; t _{CK} = t _{CK} (I _{CC}), t _{RC} = t _{RC} (I _{CC}), t _{RAS} = t _{RASmin} (I _{CC}); CE is HIGH, CS# is HIGH between valid commands; Address bus inputs are SWITCHING; Data bus inputs are SWITCHING	2,390	2,120	mA	
I _{CC1}	Operating one bank active-read-precharge current; I _{OUT} = 0mA; BL = 4, CL = CL(I _{CC}), AL = 0; t _{CK} = t _{CK} (I _{CC}), t _{RC} = t _{RC} (I _{CC}), t _{RAS} = t _{RASmin} (I _{CC}), t _{RCD} = t _{RCD} (I _{CC}); CE is HIGH, CS# is HIGH between valid commands; Address bus inputs are SWITCHING; Data pattern is same as I _{DAD6W}	2,660	2,390	mA	
I _{CC2P}	Precharge power-down current; All banks idle; t _{CK} = t _{CK} (I _{CC}); CE is LOW; Other control and address bus inputs are STABLE; Data bus inputs are FLOATING	680	644	mA	
I _{CC2Q}	Precharge quiet standby current; All banks idle; t _{CK} = t _{CK} (I _{CC}); CE is HIGH, CS# is HIGH; Other control and address bus inputs are STABLE; Data bus inputs are FLOATING	950	860	mA	
I _{CC2N}	Precharge standby current; All banks idle; t _{CK} = t _{CK} (I _{CC}); CE is HIGH, CS# is HIGH; Other control and address bus inputs are SWITCHING; Data bus inputs are SWITCHING	1,040	950	mA	
I _{CC3P}	Active power-down current; All banks open; t _{CK} = t _{CK} (I _{CC}); CE is LOW; Other control and address bus inputs are STABLE; Data bus inputs are FLOATING	Fast PDN Exit MRS(12) = 0	1,220	1,130	mA
		Slow PDN Exit MRS(12) = 1	950	860	mA
I _{CC3N}	Active standby current; All banks open; t _{CK} = t _{CK} (I _{CC}), t _{RAS} = t _{RASmax} (I _{CC}), t _{RP} = t _{RP} (I _{CC}); CE is HIGH, CS# is HIGH between valid commands; Other control and address bus inputs are SWITCHING; Data bus inputs are SWITCHING	1,670	1,580	mA	
I _{DAD6W}	Operating burst write current; All banks open, Continuous burst writes; BL = 4, CL = CL(I _{CC}), AL = 0; t _{CK} = t _{CK} (I _{CC}), t _{RAS} = t _{RASmax} (I _{CC}), t _{RP} = t _{RP} (I _{CC}); CE is HIGH, CS# is HIGH between valid commands; Address bus inputs are SWITCHING; Data bus inputs are SWITCHING	3,560	3,020	mA	
I _{DAD6R}	Operating burst read current; All banks open, Continuous burst reads, I _{OUT} = 0mA; BL = 4, CL = CL(I _{CC}), AL = 0; t _{CK} = t _{CK} (I _{CC}), t _{RAS} = t _{RASmax} (I _{CC}), t _{RP} = t _{RP} (I _{CC}); CE is HIGH, CS# is HIGH between valid commands; Address bus inputs are SWITCHING; Data pattern is same as I _{DAD6W}	3,560	3,020	mA	
I _{CC5B}	Burst auto refresh current; t _{CK} = t _{CK} (I _{CC}); Refresh command at every t _{RFC} (I _{CC}) interval; CE is HIGH, CS# is HIGH between valid commands; Other control and address bus inputs are SWITCHING; Data bus inputs are SWITCHING	5,000	4,640	mA	
I _{CC6}	Self refresh current; CK and CK# at 0V; CE 0.2V; Other control and address bus inputs are FLOATING; Data bus inputs are FLOATING	108	108	mA	
I _{CC7}	Operating bank interleave read current; All bank interleaving reads, I _{OUT} = 0mA; BL = 4, CL = CL(I _{CC}), AL = t _{RCD} (I _{CC}) - 1 * t _{CK} (I _{CC}); t _{CK} = t _{CK} (I _{CC}), t _{RC} = t _{RC} (I _{CC}), t _{RRD} = t _{RRD} (I _{CC}), t _{RCD} = 1 * t _{CK} (I _{CC}); CE is HIGH, CS# is HIGH between valid commands; Address bus inputs are STABLE during DESELECTs; Data pattern is same as I _{DAD6R} ; Refer to the following page for detailed timing conditions	5,900	5,540	mA	

Note: I_{CC} specification is based on ELPIDA components. Other DRAM Manufacturers specification may be different.

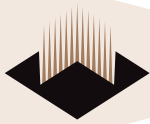


DDR2 SDRAM COMPONENT AC TIMING PARAMETERS & SPECIFICATIONS

V_{CC} = +1.8V ± 0.1V

AC CHARACTERISTICS			534		403			
PARAMETER			SYMBOL	MIN	MAX	MIN	MAX	UNIT
Clock	Clock cycle time	CL = 4	t _{CK (4)}	3,750	8,000	5,000	8,000	ps
		CL = 3	t _{CK (3)}	5,000	8,000	5,000	8,000	ps
	CK high-level width		t _{CH}	0.45	0.55	0.45	0.55	t _{CK}
	CK low-level width		t _{CL}	0.45	0.55	0.45	0.55	t _{CK}
	Half clock period		t _{HP}	MIN (t _{CH} , t _{CL})		MIN (t _{CH} , t _{CL})		ps
	Clock jitter		t _{lT}	-125	125	-125	125	ps
Data	DQ output access time from CK/CK#		t _{AC}	-500	+500	-600	+600	ps
	Data-out high-impedance window from CK/CK#		t _{HZ}		t _{AC} MAX		t _{AC} MAX	ps
	Data-out low-impedance window from CK/CK#		t _{LZ}	t _{AC} MIN	t _{AC} MAX	t _{AC} MIN	t _{AC} MAX	ps
	DQ and DM input setup time relative to DQS		t _{DS}	100		150		ps
	DQ and DM input hold time relative to DQS		t _{DH}	225		275		ps
	A DQ and DM input pulse width (for each input)		t _{dlPW}	0.35		0.35		t _{CK}
	Data hold skew factor		t _{OHS}		400		450	ps
	DQ...DQS hold, DQS to first DQ to go nonvalid, per access		t _{OH}	t _{HP} - t _{OHS}		t _{HP} - t _{OHS}		ps
	Data valid output window (DVW)		t _{DVW}	t _{OH} - t _{DQSQ}		t _{OH} - t _{DQSQ}		ns
Data Strobe	DQS input high pulse width		t _{DQSH}	0.35		0.35		t _{CK}
	DQS input low pulse width		t _{DQSL}	0.35		0.35		t _{CK}
	DQS output access time from CK/CK#		t _{DQSCCK}	-450	+450	-500	+500	ps
	DQS falling edge to CK rising ... setup time		t _{DSS}	0.2		0.2		t _{CK}
	DQS falling edge from CK rising ... hold time		t _{DSH}	0.2		0.2		t _{CK}
	DQS...DQ skew, DQS to last DQ valid, per group, per access		t _{DQSQ}		300		350	ps
	DQS read preamble		t _{RPRE}	0.9	1.1	0.9	1.1	t _{CK}
	DQS read postamble		t _{RPST}	0.4	0.6	0.4	0.6	t _{CK}
	DQS write preamble setup time		t _{WPRES}	0		0		ps
	DQS write preamble		t _{WPRE}	0.35		0.35		t _{CK}
	DQS write postamble		t _{WPST}	0.4	0.6	0.4	0.6	t _{CK}
	Write command to first DQS latching transition		t _{DQSS}	WL - 0.25	WL + 0.25	WL - 0.25	WL + 0.25	t _{CK}

Continued on next page



DDR2 SDRAM COMPONENT AC TIMING PARAMETERS & SPECIFICATIONS (cont'd)

V_{CC} = +1.8V ± 0.1V

AC CHARACTERISTICS			534		403		
PARAMETER		SYMBOL	MIN	MAX	MIN	MAX	UNIT
Command and Address	Address and control input pulse width for each input	t _{IPW}	0.6		0.6		t _{CK}
	Address and control input setup time	t _{IS}	250		350		ps
	Address and control input hold time	t _{IH}	375		475		ps
	CAS# to CAS# command delay	t _{CCD}	2		2		t _{CK}
	ACTIVE to ACTIVE (same bank) command	t _{RC}	60		55		ns
	ACTIVE bank a to ACTIVE bank b command	t _{RRD}	7.5		7.5		ns
	ACTIVE to READ or WRITE delay	t _{RCD}	15		15		ns
	Four Bank Activate period	t _{FAW}	37.5	37.5	37.5	37.5	ns
	ACTIVE to PRECHARGE command	t _{RAS}	45	70,000	40	70,000	ns
	Internal READ to precharge command delay	t _{RTP}	7.5		7.5		ns
	6 Write recovery time	t _{WR}	15		15		ns
	Auto precharge write recovery + precharge time	t _{DAL}	t _{WR} + t _{RP}		t _{WR} + t _{RP}		ns
	Internal WRITE to READ command delay	t _{WTR}	7.5		10		ns
	PRECHARGE command period	t _{RP}	15		15		ns
	PRECHARGE ALL command period	t _{RPA}	t _{RP} + t _{CK}		t _{RP} + t _{CK}		ns
	LOAD MODE command cycle time	t _{MRD}	2		2		t _{CK}
	OCD Drive mode delay	t _{OHT}	0	12	0	12	ns
	CKE low to CK,CK# uncertainty	t _{DELAY}	t _{IS} + t _{CK} + t _{IH}		t _{IS} + t _{CK} + t _{IH}		ns
Refresh	REFRESH to REFRESH command interval	t _{RFC}	105	70,000	105	70,000	ns
	Average periodic refresh interval	t _{REFI}		7.8		7.8	μs
Self Refresh	Exit self refresh to non-READ command	t _{BSNR}	t _{RFC} (MIN) + 10		t _{RFC} (MIN) + 10		ns
	Exit self refresh to READ command	t _{BSRD}	200		200		t _{CK}
	Exit self refresh timing reference	t _{LSXR}	t _{IS}		t _{IS}		ps
	Exit self refresh timing reference	t _{LSXR}	250		350		ps
ODT	ODT turn-on delay	t _{AO_{ND}}	2	2	2	2	t _{CK}
	ODT turn-on	t _{AON}	t _{AC} (MIN)	t _{AC} (MAX) + 1000	t _{AC} (MIN)	t _{AC} (MAX) + 1000	ps
	ODT turn-off delay	t _{AO_{FD}}	2.5	2.5	2.5	2.5	t _{CK}
	ODT turn-off	t _{AOF}	t _{AC} (MIN)	t _{AC} (MAX) + 600	t _{AC} (MIN)	t _{AC} (MAX) + 600	ps
	ODT turn-on (power-down mode)	t _{AO_{NP}}	t _{AC} (MIN) + 2000	2 x t _{CK} + t _{AC} (MAX) + 1000	t _{AC} (MIN) + 2000	2 x t _{CK} + t _{AC} (MAX) + 1000	ps
	ODT turn-off (power-down mode)	t _{AO_{FP}}	t _{AC} (MIN) + 2000	2.5 x t _{CK} + t _{AC} (MAX) + 1000	t _{AC} (MIN) + 2000	2.5 x t _{CK} + t _{AC} (MAX) + 1000	ps
	ODT to power-down entry latency	t _{AN_{PD}}	3		3		t _{CK}
	ODT power-down exit latency	t _{AX_{PD}}	8		8		t _{CK}
Power-Down	Exit active power-down to READ command, MR[bit12=0]	t _{XARD}	2		2		t _{CK}
	Exit active power-down to READ command, MR[bit12=1]	t _{XARDS}	6 - AL		6 - AL		t _{CK}
	A Exit precharge power-down to any non-READ command.	t _{XP}	2		2		t _{CK}
	CKE minimum high/low time	t _{CKE}	3		3		t _{CK}



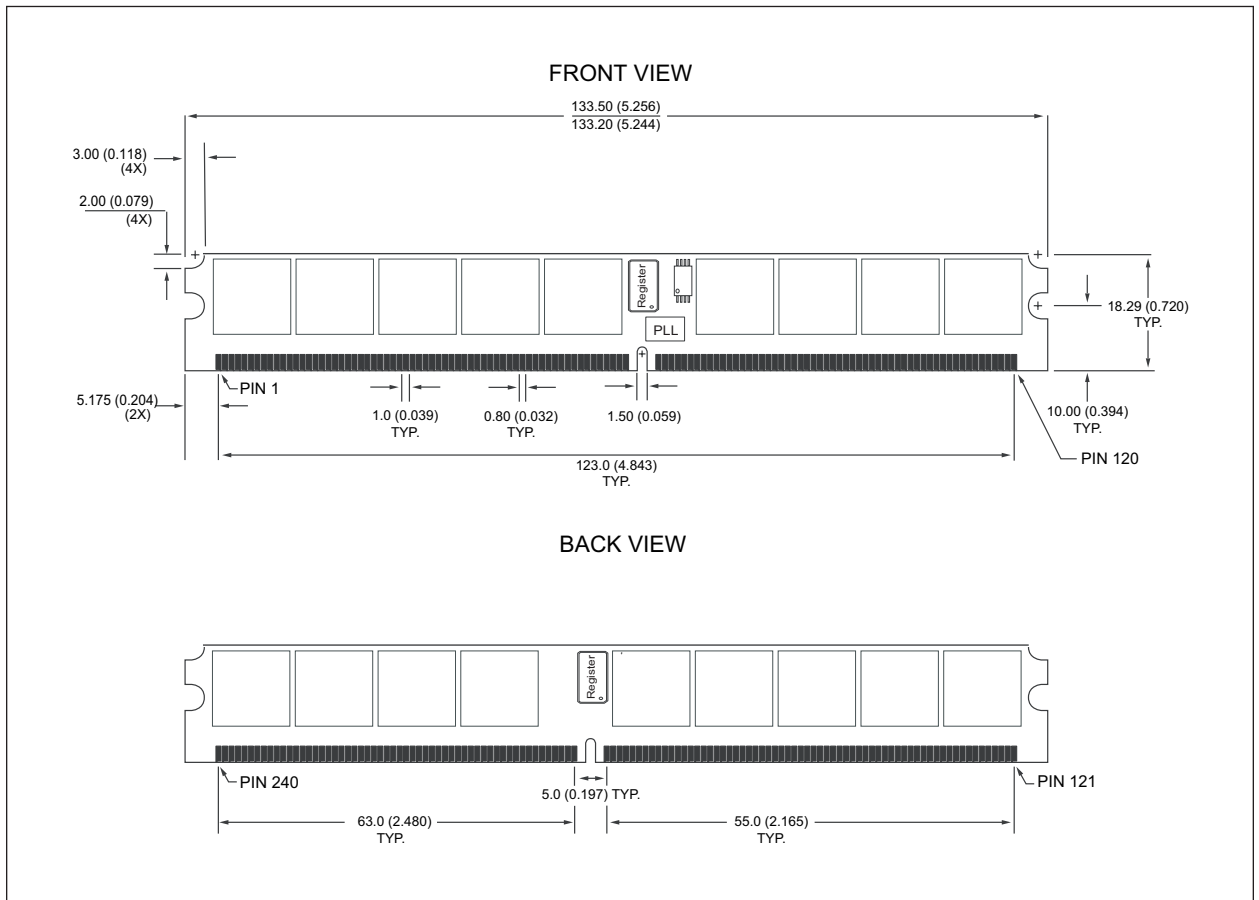
ORDERING INFORMATION FOR AD6

Part Number	Speed/Data Rate	CAS Latency	t _{RC} D	t _{RP}	Height*
WV3HG128M72AER534AD6xxG	266MHz/533Mb/s	4	4	4	18.29mm (0.72")
WV3HG128M72AER403AD6xxG	200MHz/400Mb/s	3	3	3	18.29mm (0.72")

NOTES:

- RoHS products. (*G* = RoHS Compliant)
- Vendor specific part numbers are used to provide memory component source control. The place holder for this is shown as a lower case "x" in the part numbers above and is to be replaced with respective vendors code. Consult factory for qualified sourcing options.
(E = Elpida, M = Micron, S = Samsung & consult factory for others)
- Consult factory for availability of industrial temperature (-40°C to 85°C) option

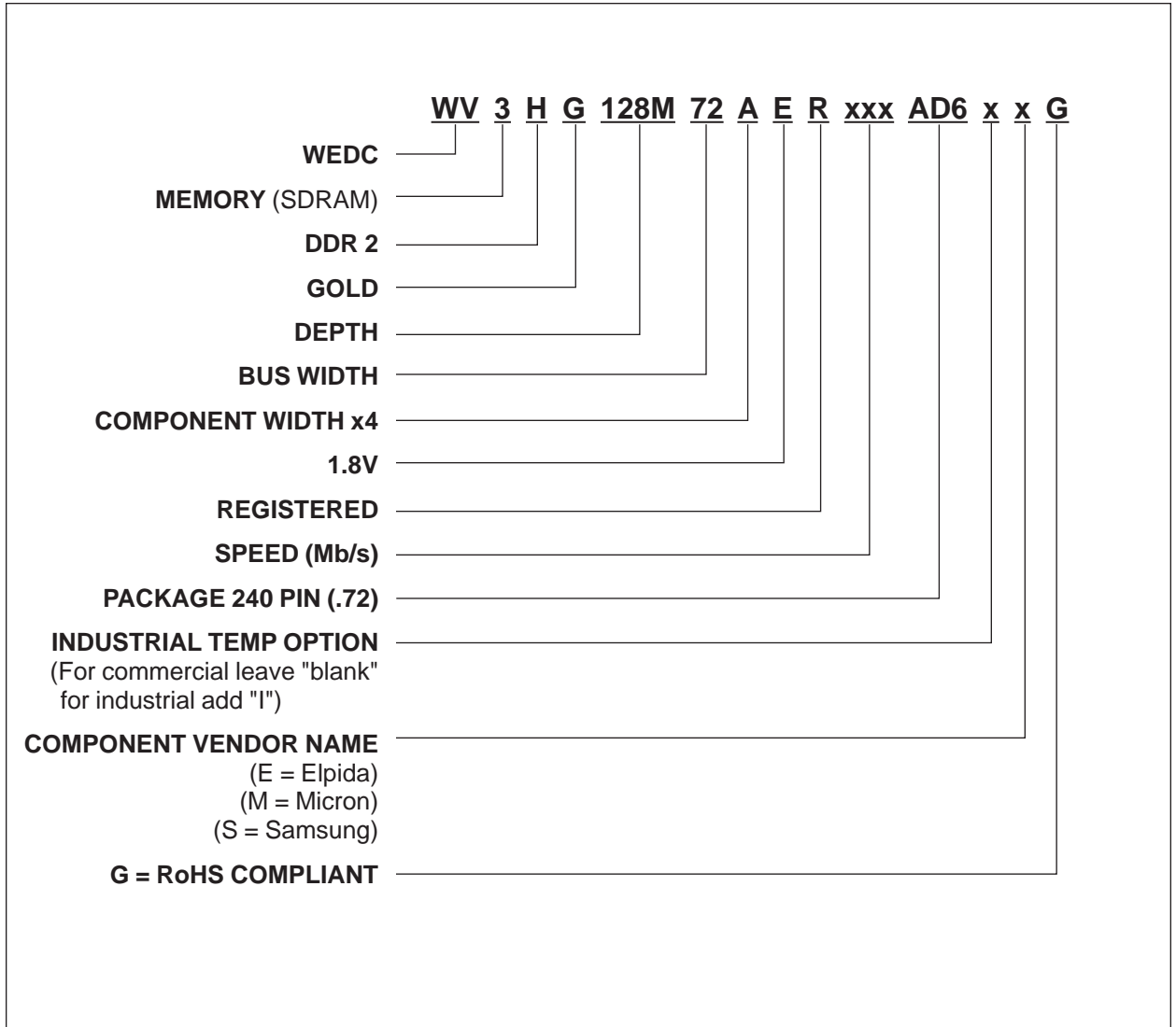
PACKAGE DIMENSIONS FOR AD6



* ALL DIMENSIONS ARE IN MILLIMETERS AND (INCHES)



PART NUMBERING GUIDE





Document Title

1GB – 128Mx72 DDR2 SDRAM REGISTERED, w/PLL

DRAM DIE OPTIONS:

- SAMSUNG: C-Die, will move to E-Die Q3'06
- MICRON: U27Y: B-Die, will move to U37Y: D-Die Q4'06
- ELPIDA: E-Die

Revision History

Rev #	History	Release Date	Status
Rev 0	Created	March 2005	Advanced
Rev 1	1.0 Updated "Absolute Maximum Ratings"	April 2006	Advanced
	1.1 Added Elpida "CAP" specifications		
	1.2 Added Elpida "Icc" specifications		
	1.3 Updated "AC Timing Parameters"		
	1.4 Added Elpida to part marking info & number guide		
	1.5 Added "Industrial Temperature" to part numbering guide		
	1.6 Added DRAM die rev option		
Rev 2	2.0 Updated AC title to indicate component AC spec only	October 2006	Advanced